

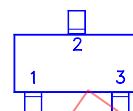
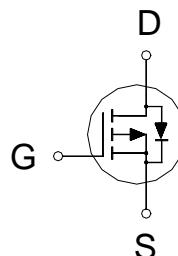
NIKO-SEM
**P-Channel Logic Level Enhancement
Mode Field Effect Transistor**
P6403FMG

SOT-23

Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-30	64m	-4A


 1 : GATE
 2 : DRAIN
 3 : SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	-4	A
	$T_C = 70^\circ\text{C}$	-3	
Pulsed Drain Current ¹	I_{DM}	-20	
Power Dissipation	$T_C = 25^\circ\text{C}$	1.25	W
	$T_C = 70^\circ\text{C}$	0.8	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$	75	100	°C / W

¹Pulse width limited by maximum junction temperature.²Duty cycle $\leq 1\%$ **ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.45	-0.8	-1.2	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 12V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -24V, V_{GS} = 0V$			-1	μA
		$V_{DS} = -20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			-10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = -5V, V_{GS} = -4.5V$	-20			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = -1.8V, I_D = -2A$	90	120		m
		$V_{GS} = -2.5V, I_D = -3A$	62	80		
		$V_{GS} = -4.5V, I_D = -4A$	55	64		
Forward Transconductance ¹	g_{fs}	$V_{DS} = -5V, I_D = -4A$	12			S

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DYNAMIC						
Input Capacitance	C_{iss}			950		
Output Capacitance	C_{oss}	$V_{GS} = 0V, V_{DS} = -15V, f = 1MHz$		115		pF
Reverse Transfer Capacitance	C_{rss}			75		
Total Gate Charge ²	Q_g			9.4		
Gate-Source Charge ²	Q_{gs}	$V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = -4.5V,$		2		nC
Gate-Drain Charge ²	Q_{gd}	$I_D = -4A$		3		
Turn-On Delay Time ²	$t_{d(on)}$			6.3		
Rise Time ²	t_r	$V_{DD} = -10V$		3.2		
Turn-Off Delay Time ²	$t_{d(off)}$	$I_D \approx -1A, V_{GS} = -4.5V, R_G = 6$		38		nS
Fall Time ²	t_f			12		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^\circ C$)						
Continuous Current	I_S				-1.6	A
Pulsed Current ³	I_{SM}				-3	
Forward Voltage ¹	V_{SD}	$I_F = -1A, V_{GS} = 0V$			-1.2	V

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

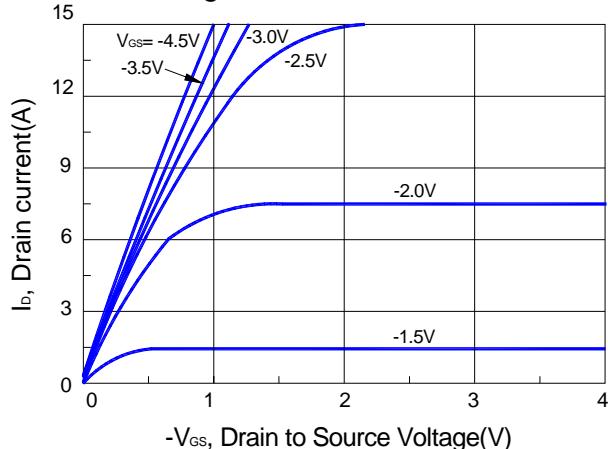
REMARK: THE PRODUCT MARKED WITH "2CYWW", DATE CODE or LOT #

Orders for parts with Lead-Free plating can be placed using the PXXXXXXG parts name.

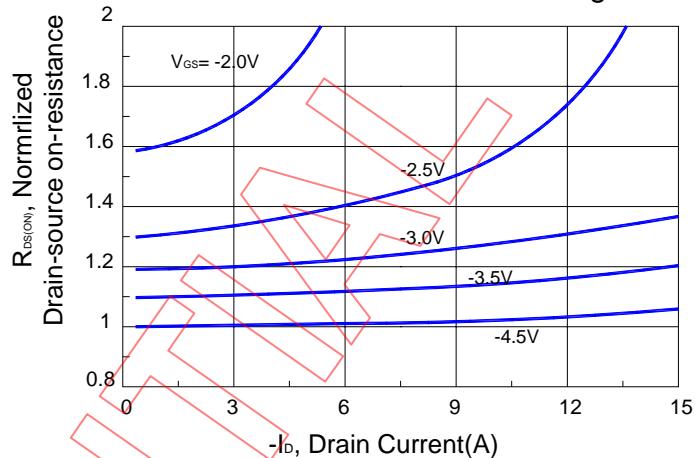
CONFIDENTIAL

Typical Electrical Characteristics

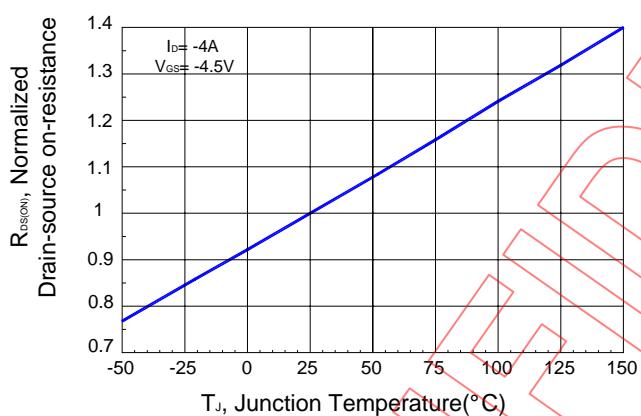
On-Region Characteristics.



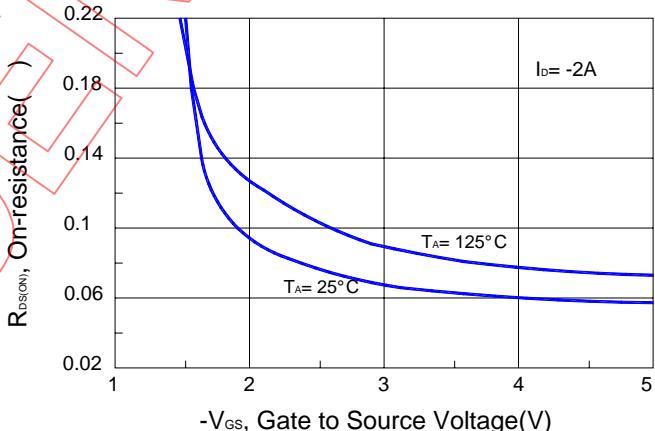
On-Resistance Variation with Drain Current and Gate Voltage.



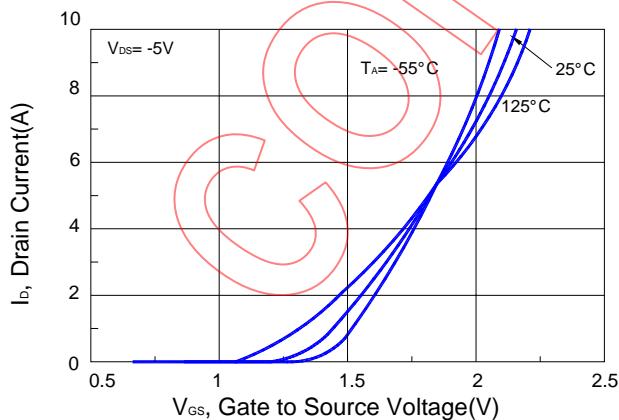
On-Resistance Variation with Temperature.



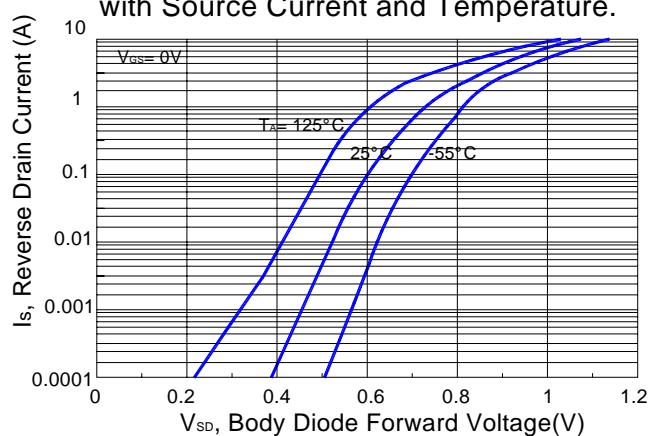
On-Resistance Variation with Gate-to-Source Voltage.



Transfer Characteristics.

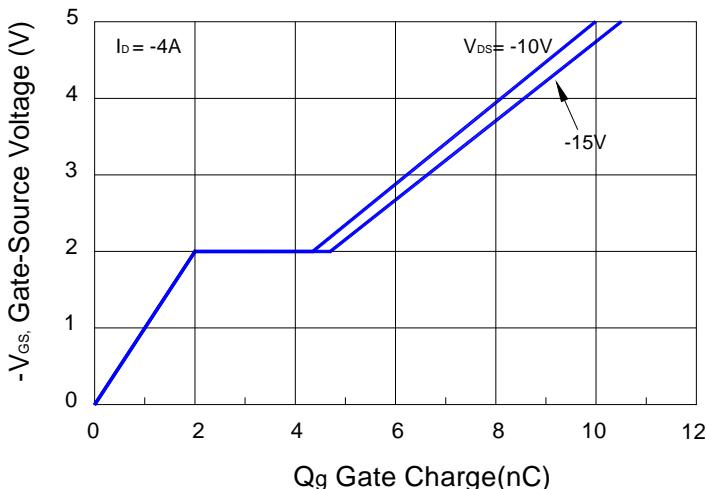


Body Diode Forward Voltage Variation with Source Current and Temperature.

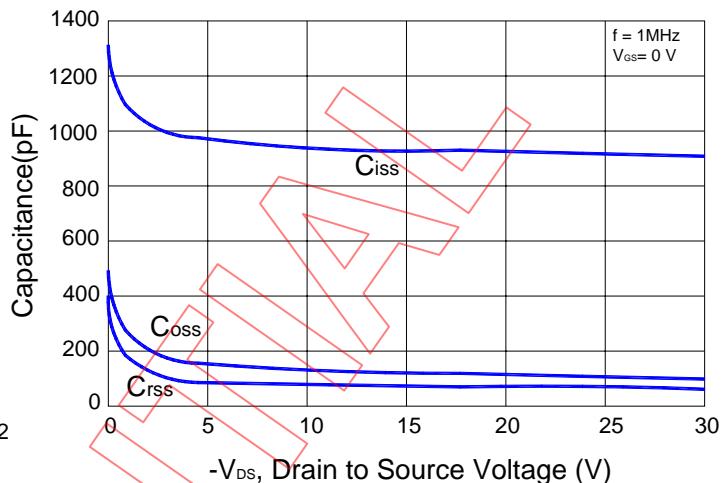


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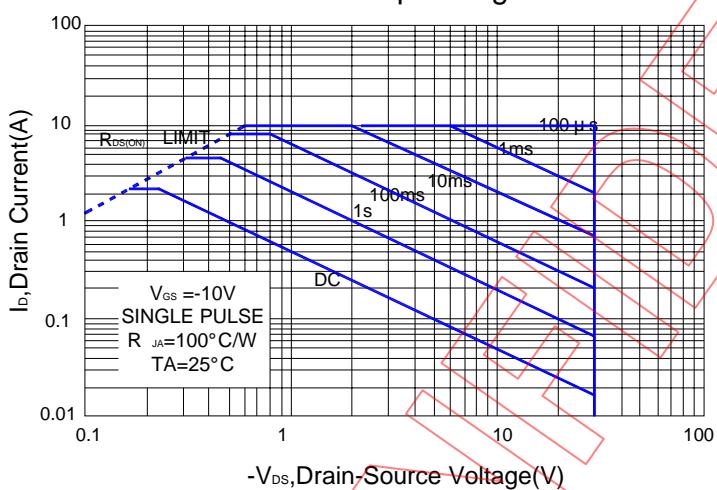
Gate-Charge Characteristics



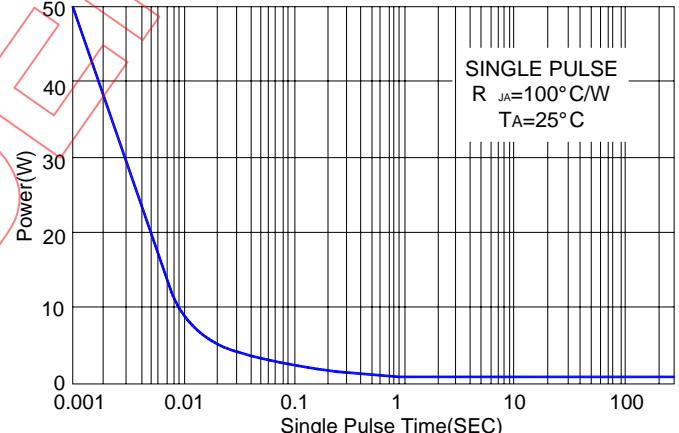
Capacitance Characteristics



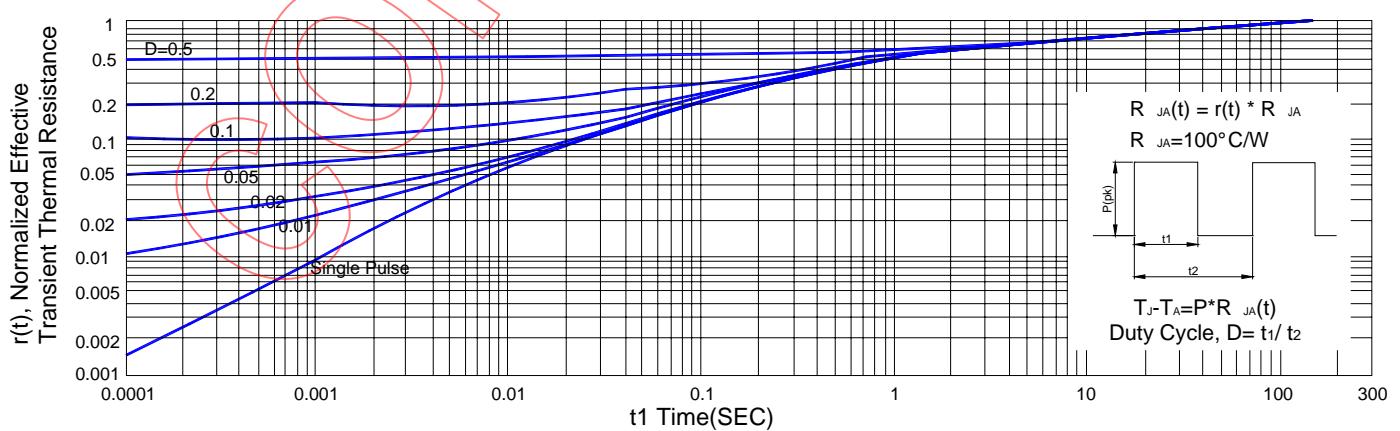
Maximum Safe Operating Area.



Single Pulse Maximum Power Dissipation.



Transient Thermal Response Curve.



SOT-23 (M3) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	0.85	0.95	1.15	H	0.1	0.15	0.35
B	2.4		3	I	0.2		0.6
C	1.4	1.6	1.8	J			
D	2.7	2.9	3.1	K			
E	0.9	1.1	1.4	L			
F	0		0.1	M			
G	0.3	0.4	0.5	N			

